


<b>Search Notes</b> 	<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
	10/607,020		HILL ET AL.	
	<b>Examiner</b>		<b>Art Unit</b>	
	Le Nguyen		2174	

SEARCHED			
Class	Subclass	Date	Examiner
715	752,963	6/21/2007	LVN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/752,963		6/21/2007	LVN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted w/Sy Luu	6/21/2007	LVN